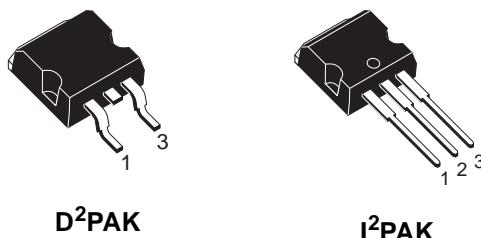


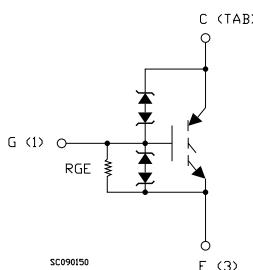
**STGB20NB32LZ****STGB20NB32LZ-1****N-CHANNEL CLAMPED 20A - D<sup>2</sup>PAK/I<sup>2</sup>PAK  
INTERNALLY CLAMPED PowerMESH™ IGBT**

TYPE	V <sub>CES</sub>	V <sub>CE(sat)</sub>	I <sub>C</sub>
STGB20NB32LZ	CLAMPED	< 2.0 V	20 A
STGB20NB32LZ-1	CLAMPED	< 2.0 V	20 A

- POLYSILICON GATE VOLTAGE DRIVEN
- LOW THRESHOLD VOLTAGE
- LOW ON-VOLTAGE DROP
- HIGH CURRENT CAPABILITY
- HIGH VOLTAGE CLAMPING FEATURE

**DESCRIPTION**

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The built in collector-gate zener exhibits a very precise active clamping while the gate-emitter zener supplies an ESD protection.

**INTERNAL SCHEMATIC DIAGRAM****APPLICATIONS**

- ELECTRONIC IGNITION FOR AUTOMOTIVE

**ORDERING INFORMATION**

SALES TYPE	MARKING	PACKAGE	PACKAGING
STGB20NB32LZT4	GB20NB32LZ	D <sup>2</sup> PAK	TAPE & REEL
STGB20NB32LZ-1	GB20NB32LZ	I <sup>2</sup> PAK	TUBE

## STGB20NB32LZ - STGB20NB32LZ-1

### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-Emitter Voltage ( $V_{GS} = 0$ )	CLAMPED	V
$V_{ECR}$	Reverse Battery Protection	20	V
$V_{GE}$	Gate-Emitter Voltage	CLAMPED	V
$I_C$	Collector Current (continuous) at $T_c = 25^\circ\text{C}$	40	A
$I_C$	Collector Current (continuous) at $T_c = 100^\circ\text{C}$	30	A
$I_{CM} (\bullet)$	Collector Current (pulsed)	80	A
$E_{as}$	Single Pulse Energy $T_c = 25^\circ\text{C}$	700	mJ
$P_{tot}$	Total Dissipation at $T_c = 25^\circ\text{C}$	150	W
	Derating Factor	1	W/ $^\circ\text{C}$
$E_{SD}$	ESD (Human Body Model)	4	kV
$T_{stg}$	Storage Temperature	-65 to 175	$^\circ\text{C}$
$T_j$	Max. Operating Junction Temperature	175	$^\circ\text{C}$

(•)Pulse width limited by safe operating area

### THERMAL DATA

R <sub>thj-case</sub>	Thermal Resistance Junction-case Max	1	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-ambient Max	62.5	°C/W

### ELECTRICAL CHARACTERISTICS (T<sub>CASE</sub> = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$BV_{(CES)}$	Clamped Voltage	$I_C = 2 \text{ mA}, V_{GE} = 0, T_c = -40^\circ\text{C}$	330	355	380	V
		$I_C = 2 \text{ mA}, V_{GE} = 0, T_c = 25^\circ\text{C}$	325	350	375	V
		$I_C = 2 \text{ mA}, V_{GE} = 0, T_c = 150^\circ\text{C}$	320	345	370	V
$BV_{(ECR)}$	Emitter Collector Break-down Voltage	$I_C = 75 \text{ mA}, T_c = 25^\circ\text{C}$	20	28		V
$BV_{GE}$	Gate Emitter Break-down Voltage	$I_G = \pm 2 \text{ mA}$	12	14	16	V
$I_{CES}$	Collector cut-off Current ( $V_{GE} = 0$ )	$V_{CE} = 15 \text{ V}, V_{GE} = 0, T_c = 150^\circ\text{C}$			10	$\mu\text{A}$
		$V_{CE} = 200 \text{ V}, V_{GE} = 0, T_c = 150^\circ\text{C}$			100	$\mu\text{A}$
$I_{GES}$	Gate-Emitter Leakage Current ( $V_{CE} = 0$ )	$V_{GE} = \pm 10 \text{ V}, V_{CE} = 0$	$\pm 400$	$\pm 660$	$\pm 1000$	$\mu\text{A}$
$R_{GE}$	Gate Emitter Resistance		10	15	25	$\text{k}\Omega$

### ON (1)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GE(th)}$	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_C = 250 \mu\text{A}, T_c = -40^\circ\text{C}$	1.2			V
		$V_{CE} = V_{GE}, I_C = 250 \mu\text{A}, T_c = 25^\circ\text{C}$	1	1.4	2	V
		$V_{CE} = V_{GE}, I_C = 250 \mu\text{A}, T_c = 150^\circ\text{C}$	0.6			V
$V_{CE(SAT)}$	Collector-Emitter Saturation Voltage	$V_{GE} = 4.5 \text{ V}, I_C = 10 \text{ A}, T_c = 25^\circ\text{C}$		1.1	1.8	V
		$V_{GE} = 4.5 \text{ V}, I_C = 10 \text{ A}, T_c = 150^\circ\text{C}$		1	1.7	V
		$V_{GE} = 4.5 \text{ V}, I_C = 20 \text{ A}, T_c = 25^\circ\text{C}$		1.35	2	V
		$V_{GE} = 4.5 \text{ V}, I_C = 20 \text{ A}, T_c = 150^\circ\text{C}$		1.25	2	V

## STGB20NB32LZ - STGB20NB32LZ-1

### ELECTRICAL CHARACTERISTICS ( $T_{CASE} = 25^\circ C$ UNLESS OTHERWISE SPECIFIED)

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs}$	Forward Transconductance	$V_{CE} = 25 V$ , $I_C = 20 A$		35		S
$C_{ies}$	Input Capacitance	$V_{CE} = 25 V$ , $f = 1 MHz$ , $V_{GE} = 0$		2300		pF
$C_{oes}$	Output Capacitance			165		pF
$C_{res}$	Reverse Transfer Capacitance			28		pF
$Q_g$	Gate Charge	$V_{CE} = 280 V$ , $I_C = 20 A$ , $V_{GE} = 5 V$		51		nC

### FUNCTIONAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_l$	Latching Current	$R_{GOFF} = 127\Omega$ , $V_{Clamp} = 250 V$ , $V_{GE} = 5 V$ , $T_C = 125^\circ C$	34			A
U.I.S.	Functional Test Open Secondary Coil	$R_{GOFF} = 1K\Omega$ , $T_C = 125^\circ C$ , $V_G = 5 V$ , $L = 1.6mH$	21.6			A

### SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ $t_r$	Delay Time Rise Time	$V_{CC} = 250 V$ , $I_C = 20 A$ $R_G = 1K\Omega$ , $V_{GE} = 4.5 V$		2.3 0.6		$\mu s$ $\mu s$
$(di/dt)_{on}$	Turn-on Current Slope	$V_{CC} = 250 V$ , $I_C = 20 A$ $R_G = 1K\Omega$ , $V_{GE} = 4.5 V$		550		A/ $\mu s$
$E_{on}$	Turn-on Switching Losses	$V_{CC} = 250 V$ , $I_C = 20 A$ , $T_c = 25^\circ C$ $R_G = 1K\Omega$ , $V_{GE} = 4.5 V$ , $T_c = 150^\circ C$		8.8 9.2		mJ mJ

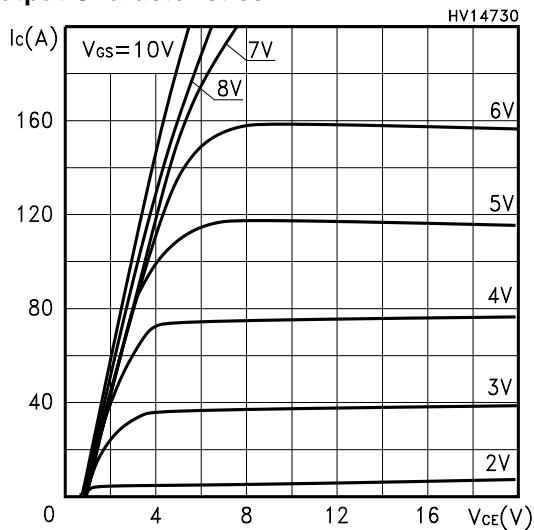
### SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_c$ $t_r(V_{off})$ $t_f$ $t_d(off)$ $E_{off}(**)$	Cross-Over Time Off Voltage Rise Time Fall Time Off Voltage Delay Time Turn-off Switching Loss	$V_{CC} = 250 V$ , $I_C = 20 A$ , $R_{GE} = 1 K\Omega$ , $V_{GE} = 4.5 V$		4.8 2.6 2 11.5 11.8		$\mu s$ $\mu s$ $\mu s$ $\mu s$ mJ
$t_c$ $t_r(V_{off})$ $t_f$ $t_d(off)$ $E_{off}(**)$	Cross-Over Time Off Voltage Rise Time Fall Time Off Voltage Delay Time Turn-off Switching Loss	$V_{CC} = 250 V$ , $I_C = 20 A$ , $R_{GE} = 1 K\Omega$ , $V_{GE} = 4.5 V$ $T_c = 150^\circ C$		7.8 3.5 3.9 12 17.8		$\mu s$ $\mu s$ $\mu s$ $\mu s$ mJ

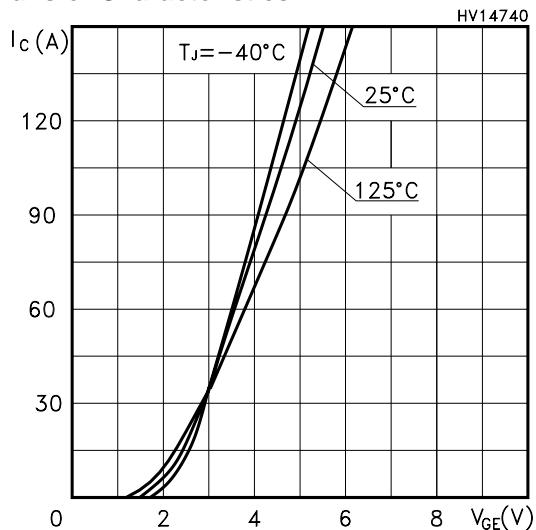
(\*\*)Losses Include Also the Tail (jedec Standardization)

## STGB20NB32LZ - STGB20NB32LZ-1

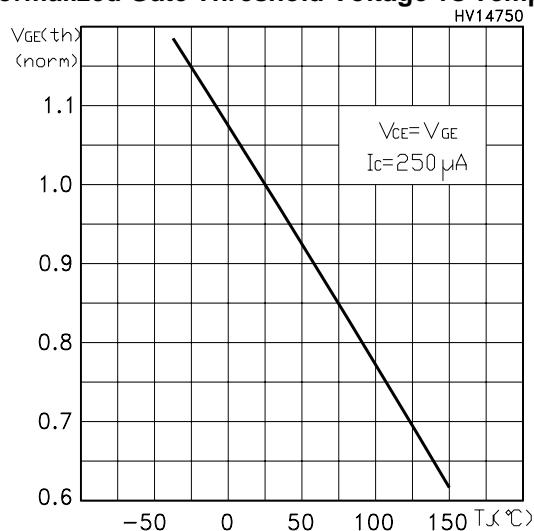
### Output Characteristics



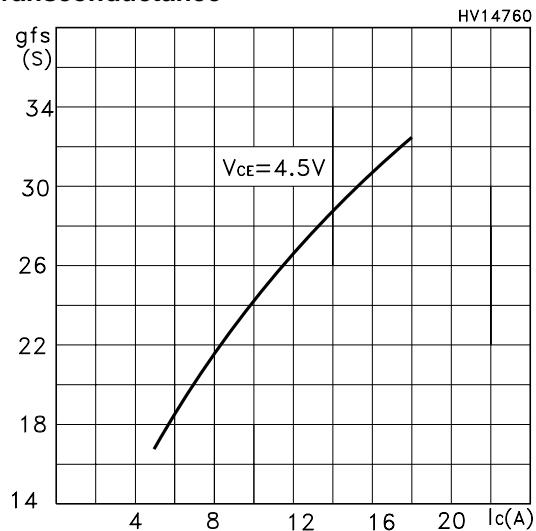
### Transfer Characteristics



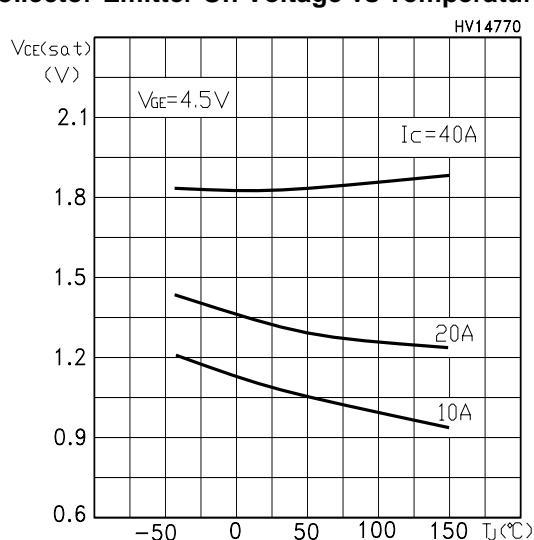
### Normalized Gate Threshold Voltage vs Temp.



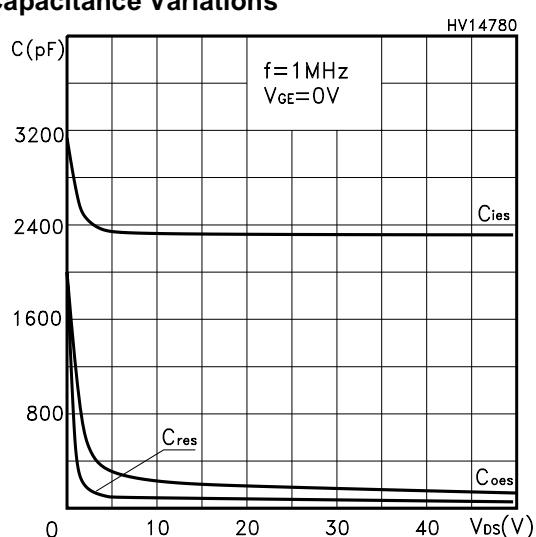
### Transconductance



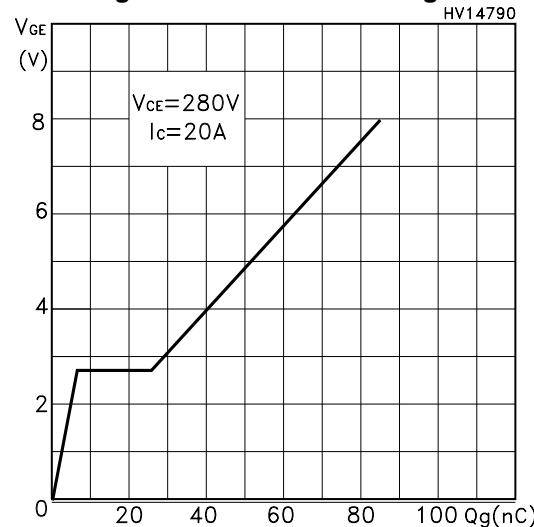
### Collector-Emitter On Voltage vs Temperature



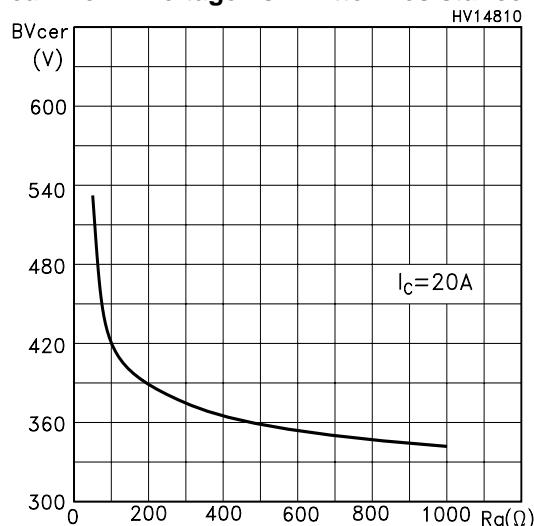
### Capacitance Variations



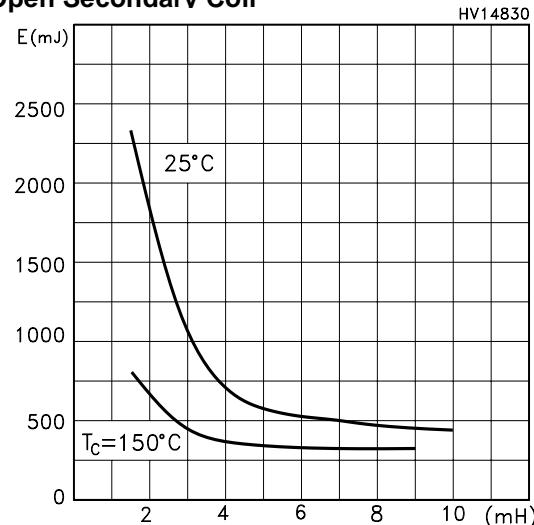
**Gate Charge vs Gate-Emitter Voltage**



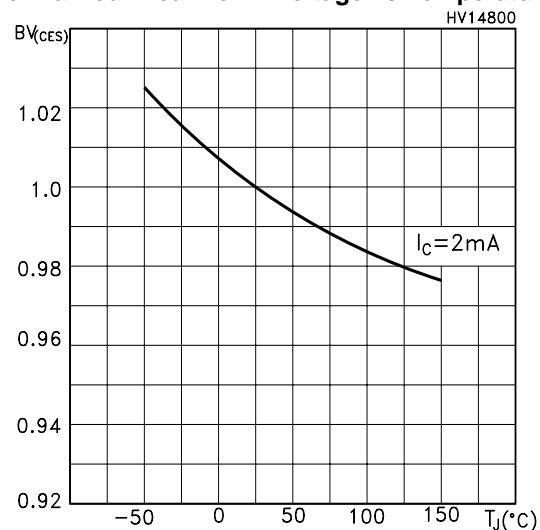
**Break-Down Voltage vs Emitter Resistance**



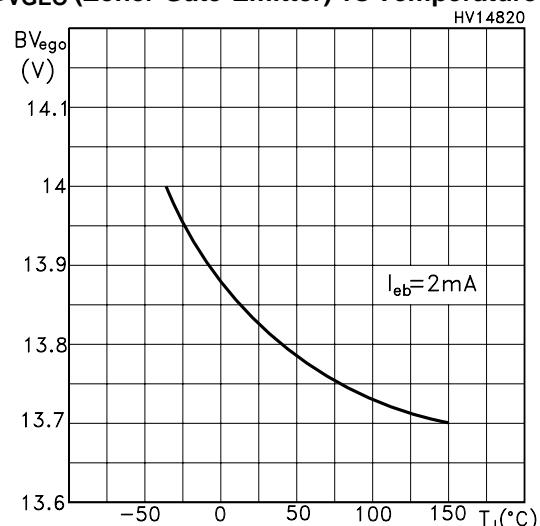
**Self Clamped Inductive Switching Energy vs Open Secondary Coil**



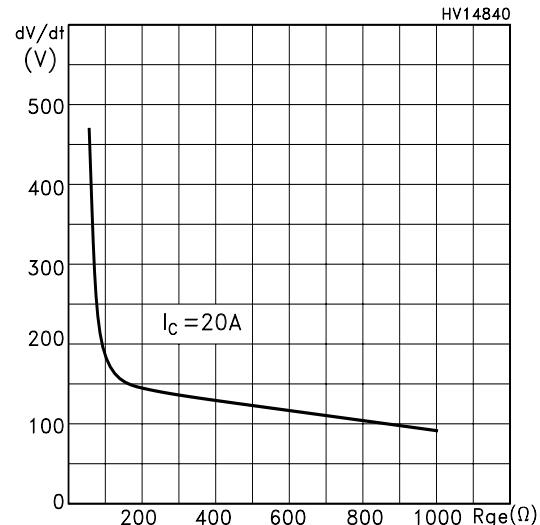
**Normalized BreakDown Voltage vs Temperature**



**$BV_{GEO}$  (Zener Gate-Emitter) vs Temperature**

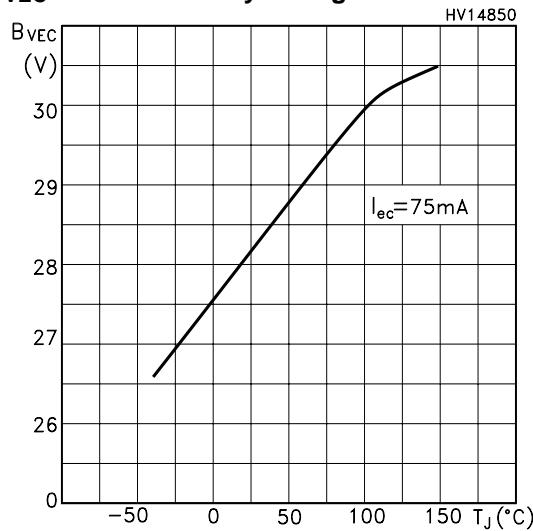


**$dV/dt$  Gate-Emitter Resistance**

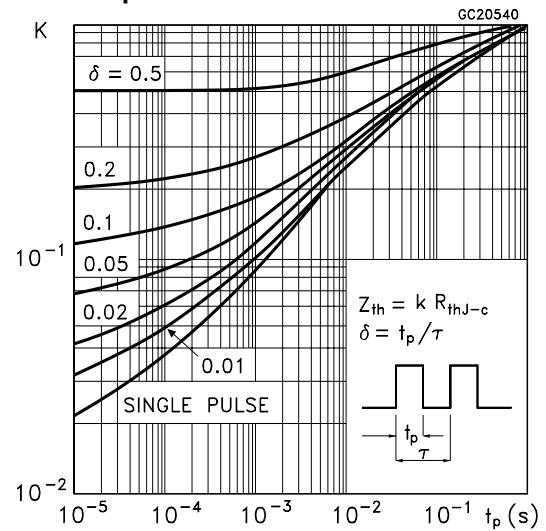


## STGB20NB32LZ - STGB20NB32LZ-1

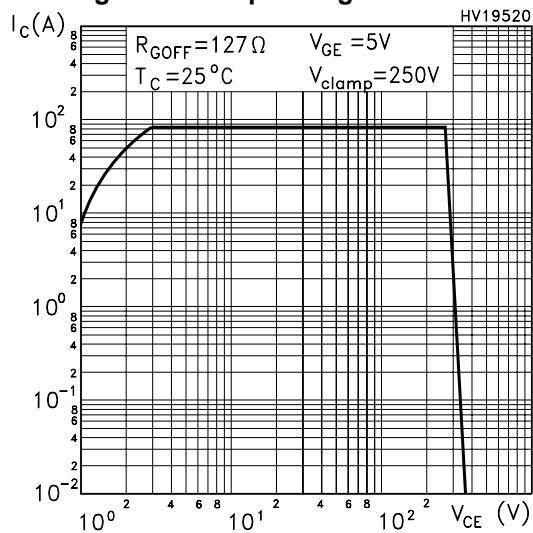
### B<sub>VEC</sub> Reverse Battery Voltage



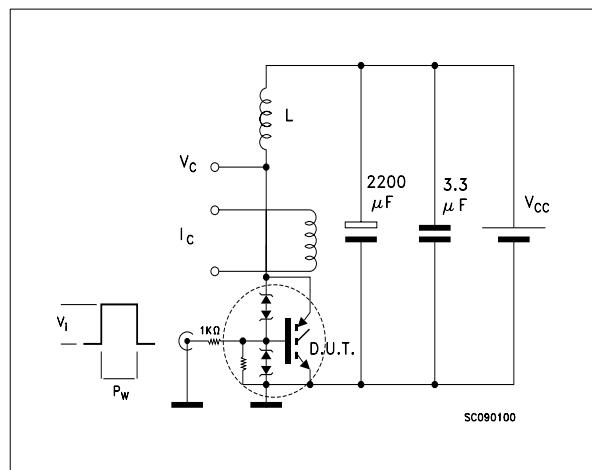
### Thermal Impedance



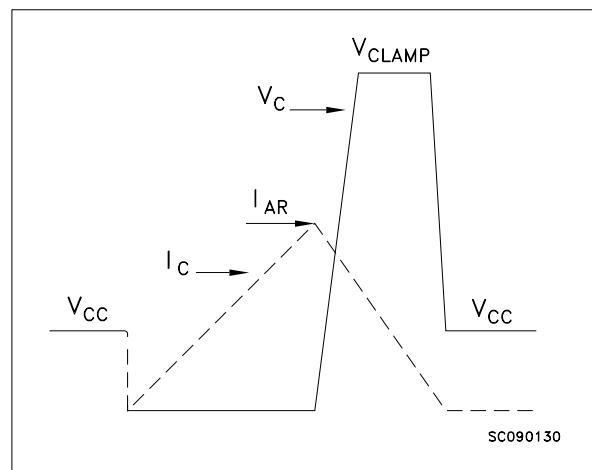
### Switching Off Safe Operating Area



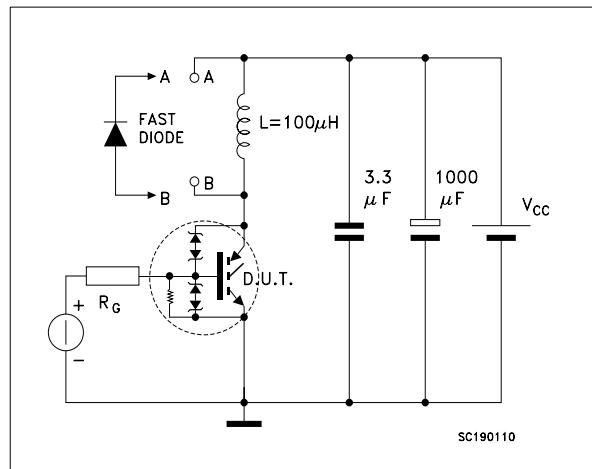
**Fig. 1:** Unclamped Inductive Load Test Circuit



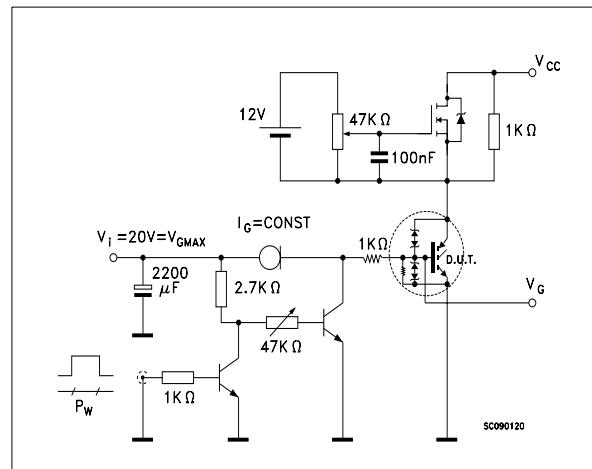
**Fig. 2:** Unclamped Inductive Waveform



**Fig. 3:** Test Circuit For Inductive Load Switching And Diode Recovery Times

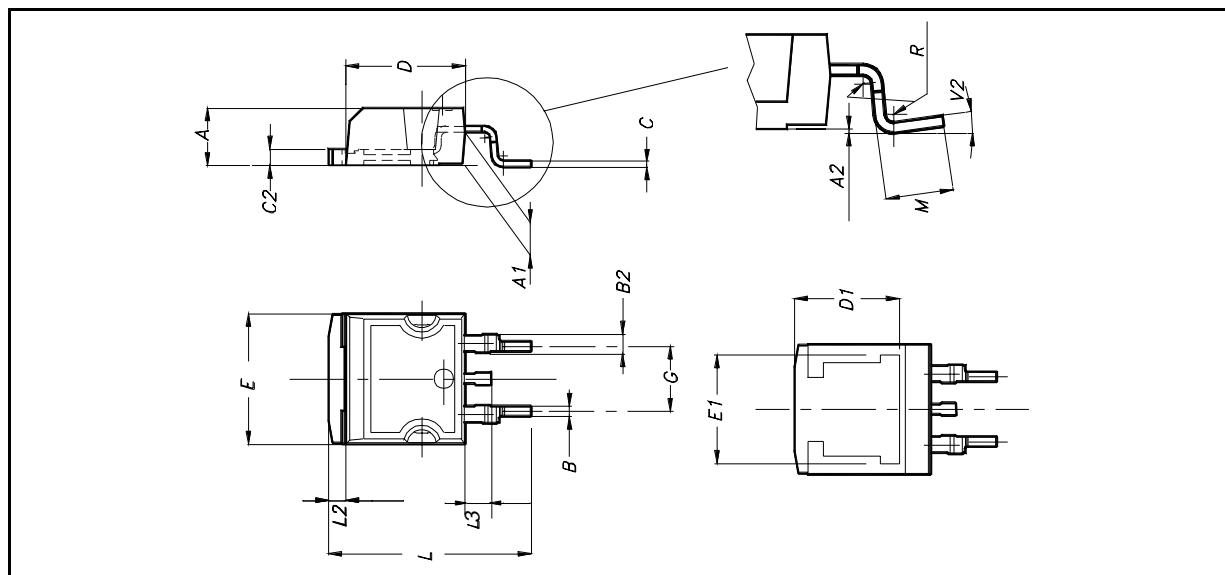


**Fig. 4:** Gate Charge test Circuit



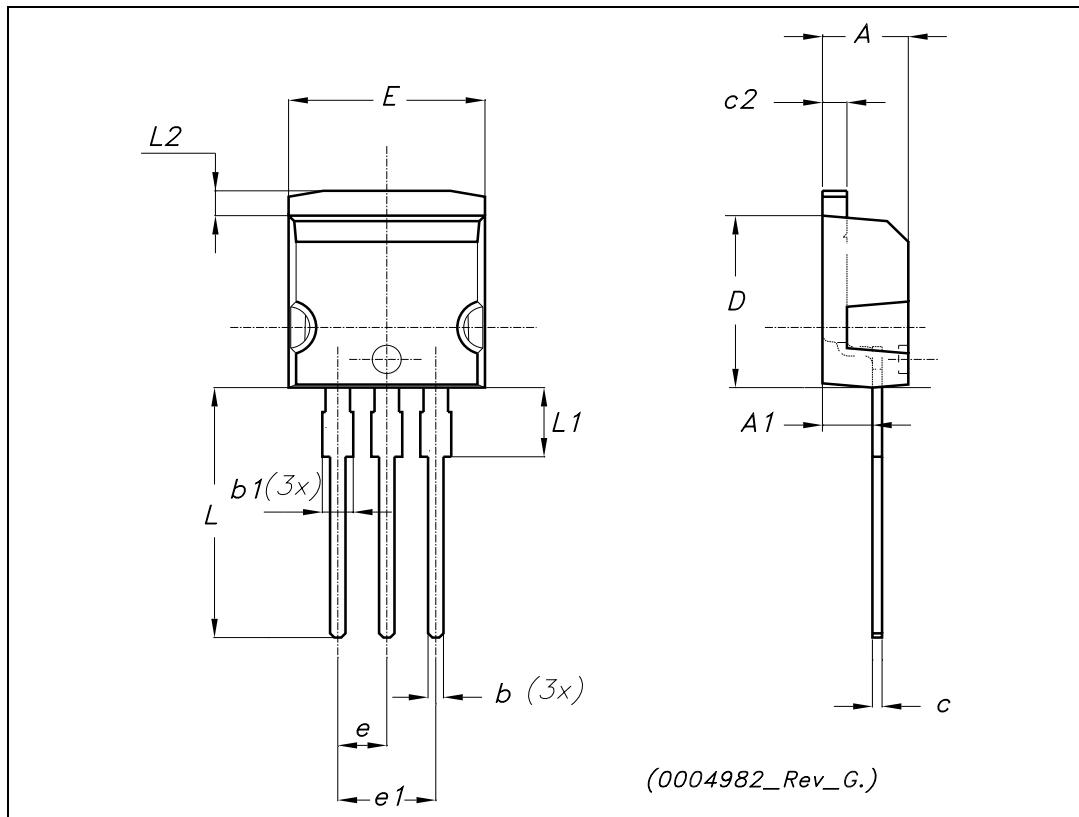
**D<sup>2</sup>PAK MECHANICAL DATA**

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
B	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
C	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
M	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	0°		8°			

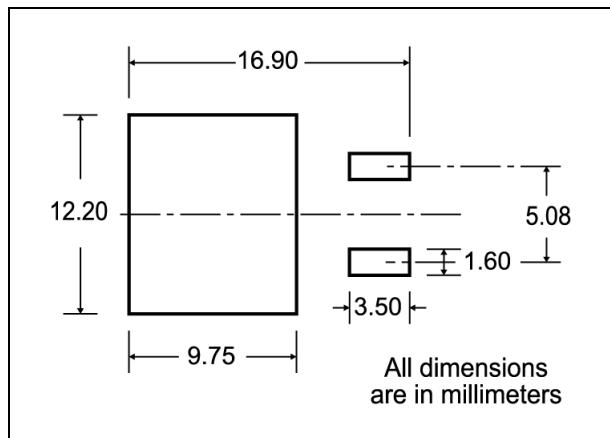


**TO-262 (I<sup>2</sup>PAK) MECHANICAL DATA**

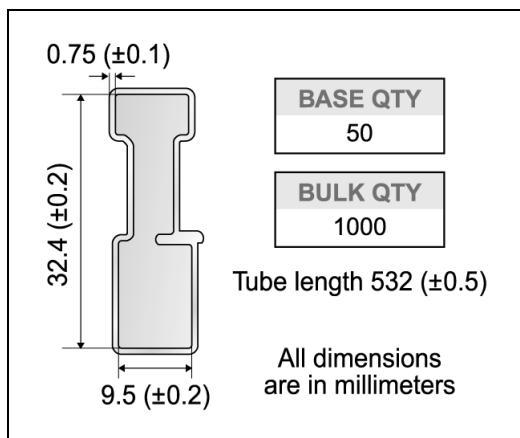
DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.40		4.60	0.173		0.181
A1	2.40		2.72	0.094		0.107
b	0.61		0.88	0.024		0.034
b1	1.14		1.70	0.044		0.066
c	0.49		0.70	0.019		0.027
c2	1.23		1.32	0.048		0.052
D	8.95		9.35	0.352		0.368
e	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
E	10		10.40	0.393		0.410
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L2	1.27		1.40	0.050		0.055



### D<sup>2</sup>PAK FOOTPRINT



### TUBE SHIPMENT (no suffix)\*



### TAPE AND REEL SHIPMENT (suffix "T4")\*

**TAPE MECHANICAL DATA**

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A0	10.5	10.7	0.413	0.421
B0	15.7	15.9	0.618	0.626
D	1.5	1.6	0.059	0.063
D1	1.59	1.61	0.062	0.063
E	1.65	1.85	0.065	0.073
F	11.4	11.6	0.449	0.456
K0	4.8	5.0	0.189	0.197
P0	3.9	4.1	0.153	0.161
P1	11.9	12.1	0.468	0.476
P2	1.9	2.1	0.075	0.082
R	50		1.574	
T	0.25	0.35	0.0098	0.0137
W	23.7	24.3	0.933	0.956

**REEL MECHANICAL DATA**

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A			330	12.992
B	1.5		0.059	
C	12.8	13.2	0.504	0.520
D	20.2		0795	
G	24.4	26.4	0.960	1.039
N	100		3.937	
T			30.4	1.197

<b>BASE QTY</b>	<b>BULK QTY</b>
1000	1000

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